AI in IoT and Embedded Devices in Smart Cities

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Deadline for manuscript submissions:
closed (15 August 2024)

Message from the Guest Editors

Dear Colleagues,

This Special Issue will focus on AI applications in smart cities. We wish to focus on IoT and embedded devices, but we are not limited to such devices. Whereas others investigate typical areas from the field of AI, we focus on IoT-optimized solutions. We will focus our attention on such topics, not limited to corpora augmentation, text generation, natural language understanding, answer generation, dialog agents, TTS, ASR, intelligent systems, smart devices, IoT tools and devices, smart cities, etc. We will also focus on their applications in other fields of science and business, especially as far as business cost reductions are concerned. We also invite convergent research articles, particularly if the generally perceived state of the art has not been established yet. We encourage you to submit papers in such areas (but not limited to solely these areas).

Special Issue

Editor-in-Chief

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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